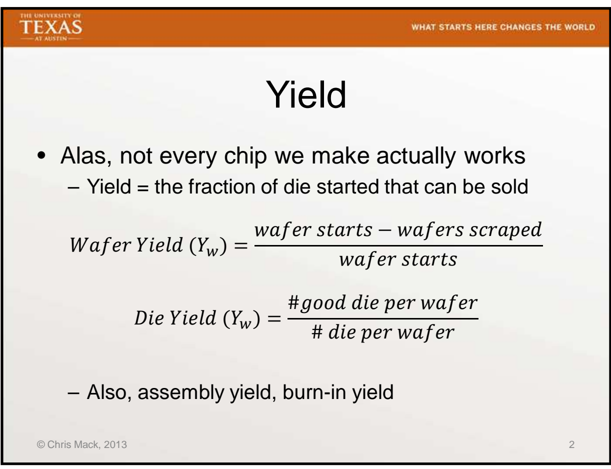

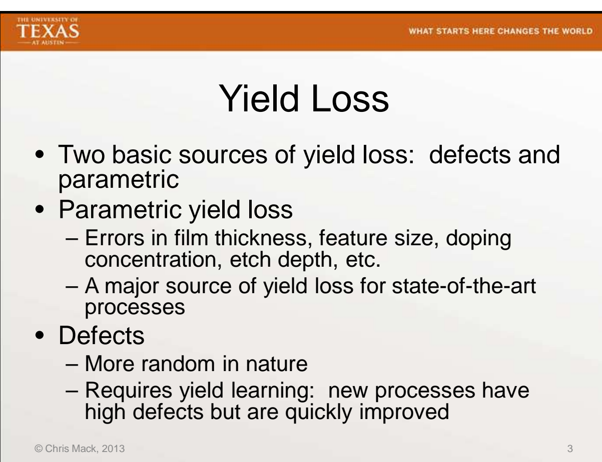

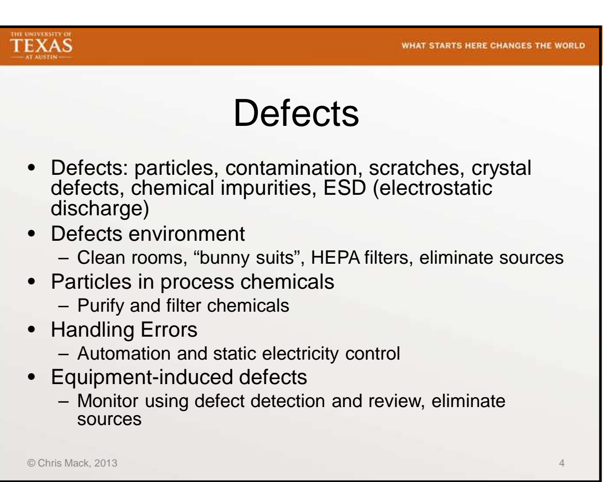

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Defect Model

- Assuming independent defects,

$$Y = (1 - G)e^{-A_c D_o}$$

G = fraction of die that always fail (edge die)
A_c = critical area (area of die where a defect matters)
D_o = defect density (# killer defects/area)

- In reality, defects often cluster, so yield is somewhat higher than this prediction

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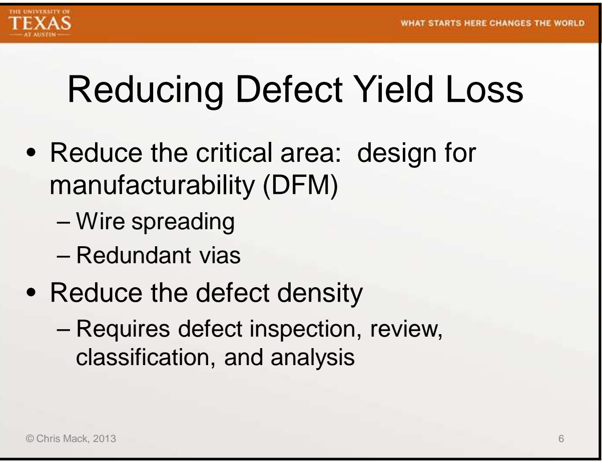

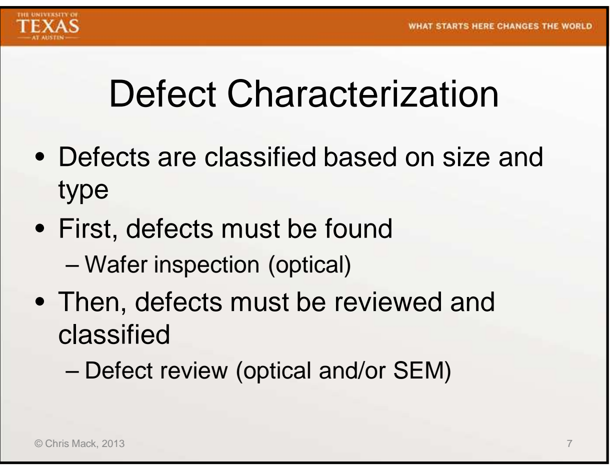

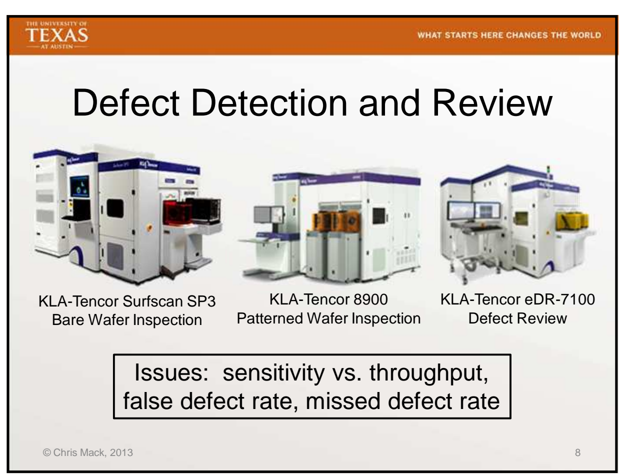

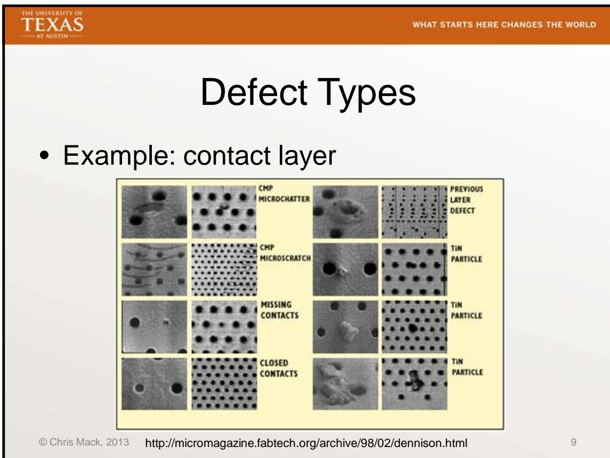

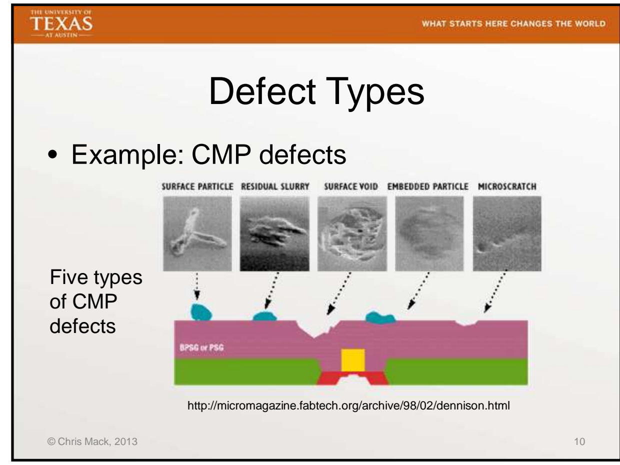

Lecture 32: What have we learned?

- What are the two major types of die yield loss?
- What are the two parameters in our simple yield model?
- What is “DFM”?

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